Chip Scale Review* The Future of Semiconductor Packaging

2017 Editorial Calendar

(Editorial close date: 11/20)	January • February	* indicates show distribution	
Industry forecast		• SEMI European 3D Summit Grenoble, France (Jan 23-25) • SMTA Pan Pac Microelectronics Symposium * Kauai, Hawaii (Feb 6-9) • SEMICON Korea Seoul, Korea (Feb 8-10) • APEX Expo San Diego, CA (Feb 14-16) • ISS Europe Munich, Germany (March 5-8) BiTS Workshop* Mesa, AZ (March 5-8) • IMAPS DPC*	
Future of packaging with silicon photonics			
FOWLP technology trends			
Cu pillars for 3D stacking			
Electroplating for packaging applications			
Electronic assembly reliability			
Metrology for lithography applications			
Package integration drives RF test complexity		Fountain Hills, AZ (March 6-9) • SEMICON China*	
High frequency test sockets		Shanghai, China (March 14-16)*	

Ad Space Close Jan 6 - Ad Materials Close Jan 11

(Editorial close date: 1/6)	March • April	* indicates show distribution	
Challenges & opportunities for OSATS		2017 ICEP Tendo, Japan (April 19-22) SEMICON SE Asia Penang, Malaysia (Apr 25-27) MEMS & Sensors Technical Congress Stanford, CA (May 10-11) ECTC * Lake Buena Vista, FL(May 30- June 2)	
Hi-accuracy metrology			
Glass-based SiP solutions			
Die attach solutions			
Electronic materials			
Embedded & fan-out packaging			
Testing of MEMS / sensors in HVM			
Wafer-level test			
Core capabilities of a thermocompression bonder			
Additive manufacturing for packaging applications			

Ad Space Close Feb 17 - Materials Close Feb 24

(Editorial close date: 3/10)	May • June	* indicates show distribution	
Recent advances & new trends in semiconductor packaging		 IEEE/SW Test Workshop (SWTW) San Diego, CA (June 5-8) Meptec MEMS & Sensors Symposium San Jose, CA (June 6) European SiPAT Networking Day* Porto, Portugal (June 22) IMAPS SiP 2017* Sonoma, CA (June 27-29) Sensors Expo & Conference San Jose, CA (June 27-29) SEMICON West * 	
WLP market update			
HD FO for HP & RF applications			
Chip scale packaging for LED applications			
Wirebond BGAs			
KGD testing		San Francisco, CA (July 12-14)	
Thin wafer handling			
3D technology failure analysis			
Feature: 50 years of CEA-Leti – past, present, future			

Ad Space Close April 21 - Ad Materials Close April 28